

**Search Notes**

Application/Control No.

10/621,885

Examiner

John Chavis

Applicant(s)/Patent under  
Reexamination

CHANG ET AL.

Art Unit

2193

**SEARCHED**

Class	Subclass	Date	Examiner
717	174	6/21/2006	JC
717	120	6/21/2006	JC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
West (IBM TDB, Derwent, EPO, JPO, PGPUBS, USPAT) anded with word search	6/21/2006	JC
Inventor search for double patenting	6/21/2006	JC